

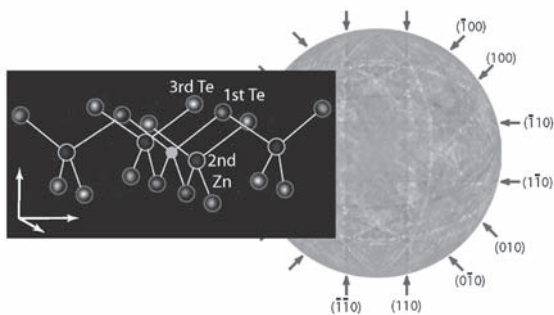
ホームページ : <http://www.sssj.org/ejsnt> 電子メール : [ejsnt@sssj.org](mailto:ejsnt@sssj.org)

J-Stage アーカイブ : <http://www.jstage.jst.go.jp/browse/ejsnt/>

### 中距離秩序構造を解き明かす蛍光X線ホログラフィ

Applications of X-ray Fluorescence Holography to Materials Sciences (Conference -Atomic Holography-2010-)  
Vol. 9, pp. 265-272 (July 9, 2011)

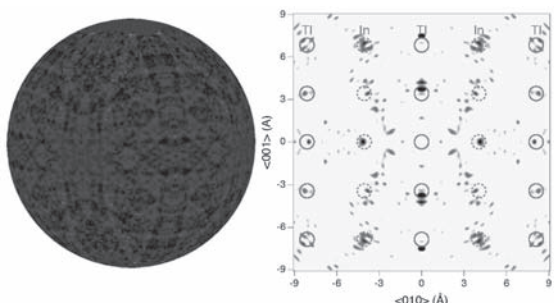
S. Hosokawa, T. Ozaki, N. Hoppo and K. Hayashi



### Tl 原子位置の揺らぎを X 線ホログラフィで解析 Three Dimensional Atomic Image of TlInSe<sub>2</sub> by X-ray Fluorescence Holography

(Conference -Atomic Holography-2010-)

K. Mimura, S. Hosokawa, N. Hoppo, W. Hu, K. Hayashi, K. Wakita, H. Ishii, M. Yoshimura, J. Jeyakanthan and N. Mamedov, Vol. 9, pp. 273-276 July 9, 2011)

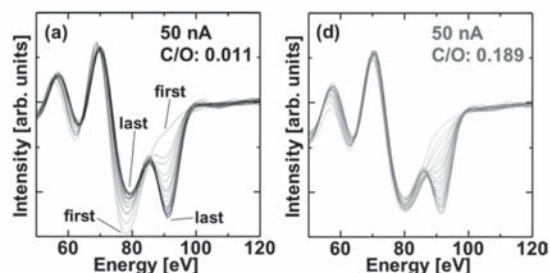


### 極微量のカーボン汚染が AES 結果を大きく左右

Approach to Quantitative Evaluation of Electron-Induced Degradation of SiO<sub>2</sub> Film Surface with Different Amounts of Carbon Contaminations

(Regular Paper) Vol. 9, pp. 277-288 (July 16, 2011)

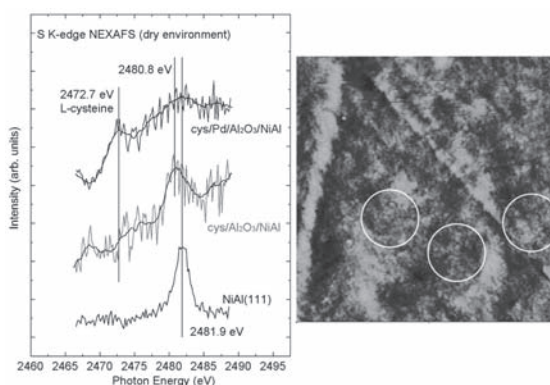
T. Nagatomi, H. Nakamura, Y. Takai and S. Tanuma



### Pd 表面へのアミノ酸分子の吸着

Adsorption Reaction of Amino Acid Molecule on Pd Thin Layer Surface Constructed by Nano-dots under Water Environment (Regular Paper)

C. Tsukada, S. Ogawa, H. Niwa, S. Yagi, T. Nomoto, G. Kuluk, H. Namatame and M. Taniguchi, Vol. 9, pp. 289-292 (July 16, 2011)

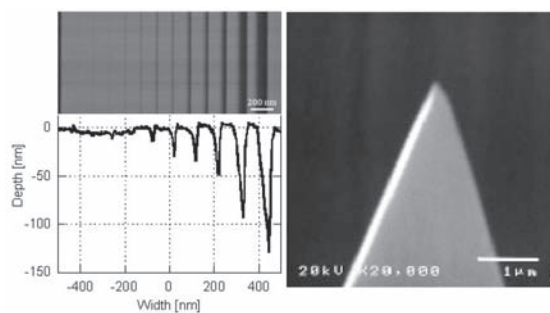


### AFM 探針の形状を計測するための標準試料

AFM Tip Characterizer fabricated by Si/SiO<sub>2</sub> multilayers (Conference -NSS-6-)

Vol. 9, pp. 293-296 (July 16, 2011)

H. Takenaka, M. Hatayama, H. Ito, T. Ohchi, A. Takano, S. Kurosawa, H. Itoh and S. Ichimura



### 直方体の形状をした Bi オキシクロライド微粒子

Synthesis of BiOCl Rectangular Nanostructures

(Regular Paper) L. Z. Pei, Y. Yang and Y. Q. Pei,

Vol. 9, pp. 297-300 (July 30, 2011)

